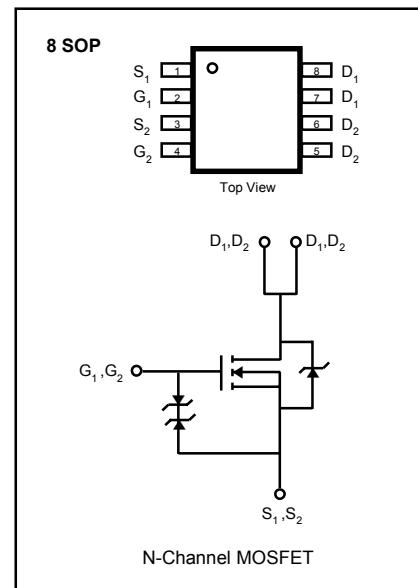


Dual N-CHANNEL POWER MOSFET

SSD2007A

FEATURES

- Extremely Lower $R_{DS(ON)}$
- Improved Inductive Ruggedness
- Fast Switching Times
- Rugged Polysilicon Gate Cell Structure
- Low Input Capacitance
- Extended Safe Operating Area
- Improved High Temperature Reliability
- Surface Mounding Package : **8SOP**



Absolute Maximum Ratings

Symbol	Characteristic	Value	Units
V _{DSS}	Drain-to-Source Voltage(1)	50	V
V _{DGR}	Drain-Gate Voltage($R_{GS}=1.0M\Omega$)(1)	50	V
V _{GS}	Gate-to-Source Voltage	± 20	V
I _D	Continuous Drain Current $T_A=25^\circ C$	2.0	A
I _D	Continuous Drain Current $T_A=100^\circ C$	1.6	A
I _{DM}	Drain Current-Pulsed (2)	8.0	V
P _D	Total Power Dissipation $T_A=25^\circ C$	2.0	W
	$T_A=70^\circ C$	1.3	
T _J , T _{STG}	Operating and Storage Junction Temperature Range	- 55 to + 150	$^\circ C$
T _L	Maximum Lead Temp. for Soldering Purposes, 1/16" from case for 5 seconds	300	

Notes :

(1) $T_J = 25^\circ C$ to $150^\circ C$

(2) Repetitive Rating : Pulse Width Limited by Max. Junction Temperature

SSD2007A

Dual N-CHANNEL
POWER MOSFET

Electrical Characteristics ($T_A=25^\circ\text{C}$ unless otherwise specified)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
BV_{DSS}	Drain-Source Breakdown Voltage	50	--	--	V	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	2.0	--	4.0	V	$\text{V}_{\text{DS}}= \text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$
I_{GSS}	Gate-Source Leakage , Forward	--	--	1.0	μA	$\text{V}_{\text{GS}}=20\text{V}$
	Gate-Source Leakage , Reverse	--	--	-1.0	μA	$\text{V}_{\text{GS}}=-20\text{V}$
I_{DSS}	Drain-to-Source Leakage Current	--	--	2	μA	$\text{V}_{\text{DS}}=50\text{V}$
		--	--	25		$\text{V}_{\text{DS}}=40\text{V}, \text{T}_J=55^\circ\text{C}$
I_{DON}	On-State Drain-Source Current(2)	8.0	--	--	A	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=5\text{V}$
$\text{R}_{\text{DS(on)}}$	Static Drain-Source On-State Resistance(2)			0.3	Ω	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=1.5\text{A}$
				0.5		$\text{V}_{\text{GS}}=5.0\text{V}, \text{I}_D=0.6\text{A}$
g_{fs}	Forward Transconductance	--	2.5	--	S	$\text{V}_{\text{DS}} \geq 15\text{V}, \text{I}_D=2.0\text{A}$
$t_{\text{d(on)}}$	Turn-On Delay Time	--	--	40	ns	$\text{V}_{\text{DD}}=30\text{V}, \text{I}_D=0.6\text{A}, \text{Z}_0=6.0\Omega,$
t_r	Rise Time	--	--	70		
$t_{\text{d(off)}}$	Turn-Off Delay Time	--	--	100		
t_f	Fall Time	--	--	70		
Q_g	Total Gate Charge	--	--	15	nC	$\text{V}_{\text{DS}}=25\text{V}, \text{V}_{\text{GS}}=10\text{V}, \text{I}_D=1.3\text{A}$
Q_{gs}	Gate-Source Charge	--	1.0	--		
Q_{qd}	Gate-Drain ("Miller") Charge	--	2.0	--		

Thermal Resistance

Symbol	Characteristic	Typ.	Max.	Units
$\text{R}_{\theta\text{JA}}$	Junction-to-Ambient	--	62.5	°C/W

Notes :

- (1) $\text{T}_J=25^\circ\text{C}$ to 150°C
- (2) Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

Source-Drain Diode Ratings and Characteristics

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
I_S	Continuous Source Current (Body Diode)	--	--	1.8	A	Modified MOSFET Symbol Showing the Integral Reverse P-N Junction Rectifier
		--	--			
		--	--			
V_{SD}	Diode Forward Voltage(2)	--	--	1.2	V	$\text{T}_J=25^\circ\text{C}, \text{I}_S=1.25\text{A}, \text{V}_{\text{GS}}=0\text{V}$
t_{rr}	Reverse Recovery Time	--	--	100	ns	$\text{T}_J=25^\circ\text{C}, \text{I}_F=2.5\text{A}, \text{di}_F/\text{dt}=100\text{A}/\mu\text{s}$

Fig 1. Output Characteristics

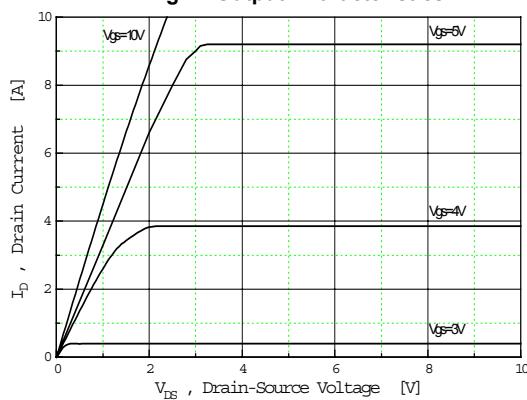


Fig 2. Transfer Characteristics

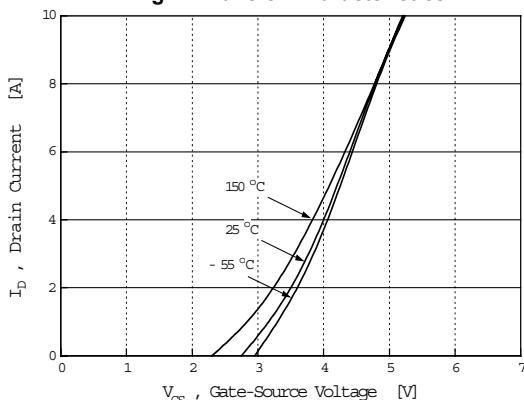


Fig 3. On-Resistance vs. Drain Current

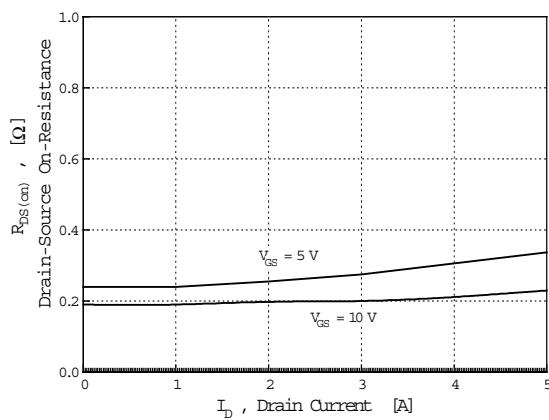


Fig 4. Capacitance vs. Drain-Source Voltage

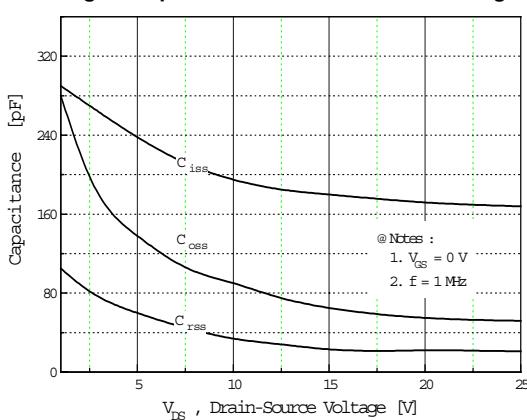


Fig 5. Breakdown Voltage vs. Temperature

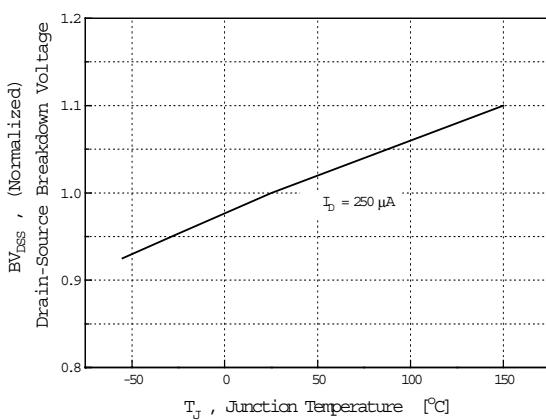


Fig 6. Normalized On-Resistance vs. Temperature

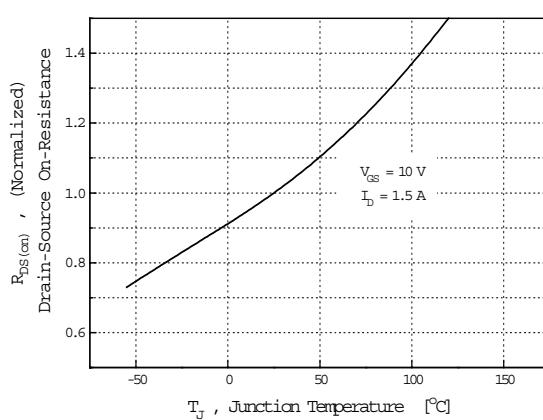


Fig 7. Normalized Effective Transient Thermal Impedance, Junction-to-Ambient

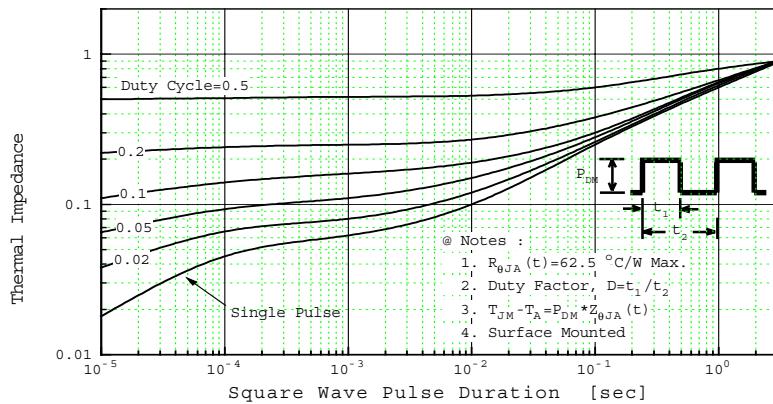


Fig 8. Source-Drain Diode Forward Voltage

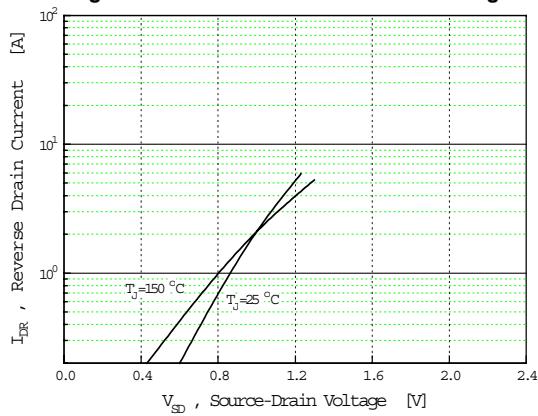


Fig 9. Gate Charge vs. Gate-Source Voltage

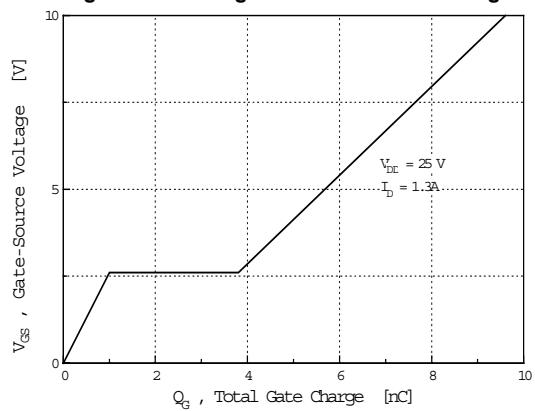
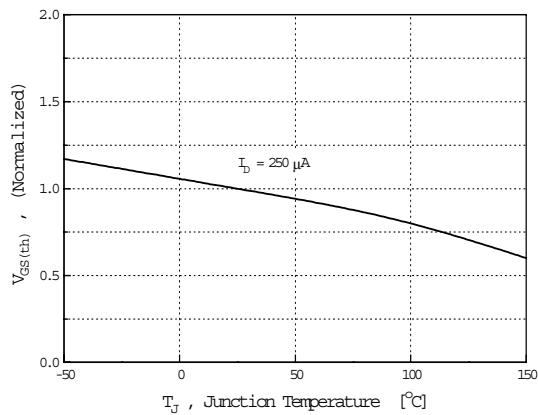


Fig 10. Threshold Voltage



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		PowerEdge™	SuperSOT™-6	

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